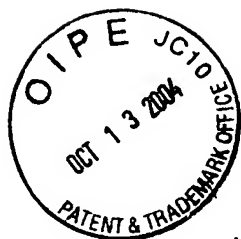


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PATENT
Customer No. 22,852
Attorney Docket No. 02887.0257

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:)
Akira HAMAGUCHI *et. al.*) Group Art Unit: 2623
Application No.: 10/687,828) Examiner: Not Assigned
Filed: October 20, 2003)
For: METHOD AND APPARATUS FOR)
DETERMINING DEFECT)
DETECTION SENSITIVITY DATA,
CONTROL METHOD OF DEFECT
DETECTION APPARATUS, AND
METHOD AND APPARATUS FOR
DETECTING DEFECT OF
SEMICONDUCTOR DEVICES

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

RESPONSE TO NOTICE OF NON-COMPLIANT AMENDMENT

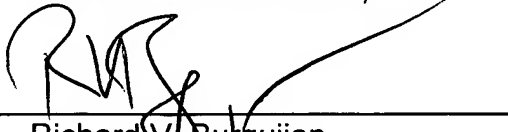
In response to the Notice of Non-Compliant of Amendment dated September 22, 2004, the period for response to which extends through October 22, 2004, Applicants submit a revised "Amendments to the claims" section of the Amendment filed on April 19, 2004. The revised "Amendments to the claims" section includes a complete listing of all claims with each claim including a proper status identifier. A copy of the Notice is also enclosed.

Please associate this corrected "Amendments to the claims" section with the application, grant any extensions of time required to enter this response, and charge any additional required fees to our deposit account 06-0916.

Respectfully submitted,

FINNEGAN, HENDERSON, FARABOW,
GARRETT & DUNNER, L.L.P.

Dated: October 13, 2004

By: 
Richard V. Burgujian
Reg. No. 31,744